
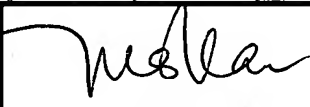



Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/815,162	WU, STEPHEN	
	Examiner	Art Unit	
	Hiep Nguyen	2816	

ISSUE CLASSIFICATION										
ORIGINAL				CROSS REFERENCE(S)						
CLASS	SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)					
327	156			327	157	117				
INTERNATIONAL CLASSIFICATION										
40	3	L	7100							
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HIEP NGUYEN 03.16.06 (Assistant Examiner) (Date)		 TUAN T. LAM PRIMARY EXAMINER (Primary Examiner)		Total Claims Allowed: 31	
 (Legal Instruments Examiner) (Date)		3/29/06 (Date)		O.G. Print Claim(s) 1	
				O.G. Print Fig. 3	

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
Final	Original	Final	Original	Final	Original	Final	Original
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